



AA3000 Scanning Probe Microscope

Features

High Performance

- Atomic-scale of resolution
- Large sample size
- With a DSP inside for great performance
- Real time operating system embedded
- Fast Ethernet connection with computer

Multi-Function

- Atomic Force Microscope (AFM)
- Scanning Tunneling Microscope (STM)

- Lateral Force Microscope (LFM)
- Force Analysis: I-V Curve, I-Z Curve, Force Curve
- Online real-time 3D image for better observation
- Multi-channel signals for more sample details
- Trace-Retrace scan, Back-Forward scan
- Multi-Analysis: Granularity and Roughness
- Data load-out for further analysis

Easy Operation

- Fast automatically tip-engaging
- Simple change the tip holder to switch between STM and AFM
- Full digital control, auto system status recognition
- Software-based sample movement
- Nano-Movie function: Continuous data collection, storage and replay
- Modularized design for convenience of maintenance and future upgrade

Specifications

Functions	Atomic Force Microscope (AFM) Scanning Tunneling Microscope(STM) Lateral Force Microscope (LFM)
Resolution	AFM: 0.26nm lateral, 0.1nm vertical Scanning Tunneling Microscope(STM)
Technical Parameters	X-Y scan scope:~10 micrometer Z distance:~2 micrometer Image Pixels:128X128, 256X256, 512X512, 1024X1024 Scan Angle:0~360 degree Scan Rate: 0.1~100Hz
Electronics	CPU: 32-bit Digital Signal Processor (DSP) at 600MHz from Texas Instruments; Fast16-bit DAC Fast16-bit ADC High Voltage: 5 channel Communication Interface: 10M/100M Fast Ethernet
Mechanics	Sample Size: Up to 45mm in diameter, reach 15mm when use a AA2000/AA3000,and reach 30mm when use the AA5000; Engagement: Auto engagement with travel distance of 30mm and precision of 50nm;
Softwares	Online Control Software and offline Image Processing Software for Windows Vista/XP/2000/9x

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